

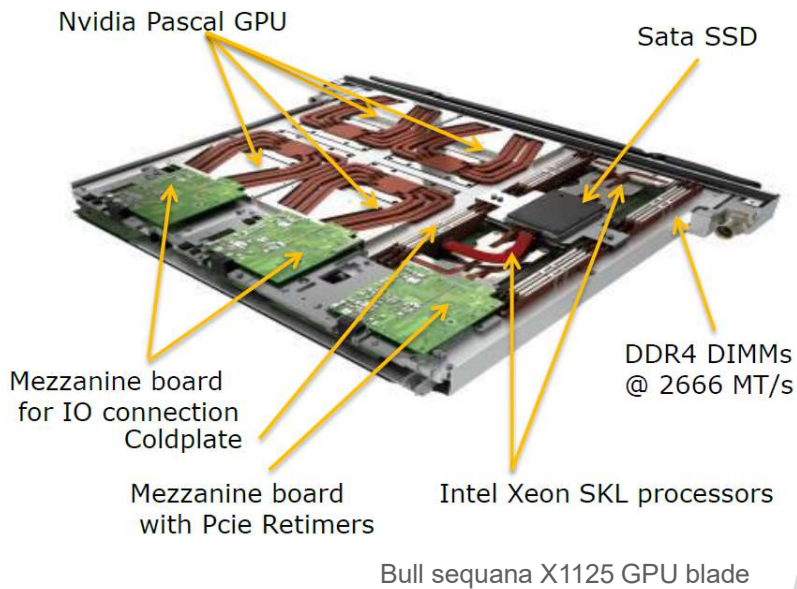
# TECHNOLOGIES FOR NEW COMPUTING PARADIGMS

Leti Devices Workshop | Carlo REITA | Dec 2nd, 2018, Nikko Hotel, San Francisco

## FUNCTIONS AND CONSTRAINTS

### Fundamental functions

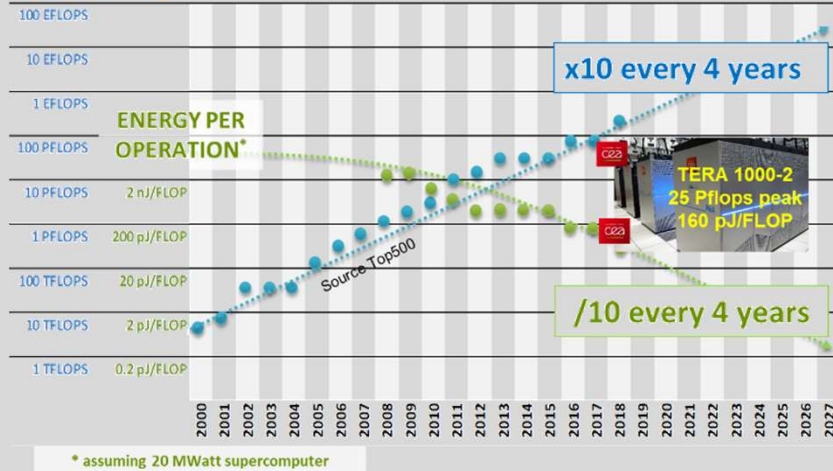
- Compute
- Store
- Transmit



### Constraints

- Power
- Cost
- Performance
- Time to Market

#### PERFORMANCE



### Fundamental functions

- Compute
- Store
- Transmit



The on-board computer in Stanford's autonomous Audi TTS. (Image courtesy of Stanford University.)

### Constraints

- Power
- Cost
- Performance
- Time to Market

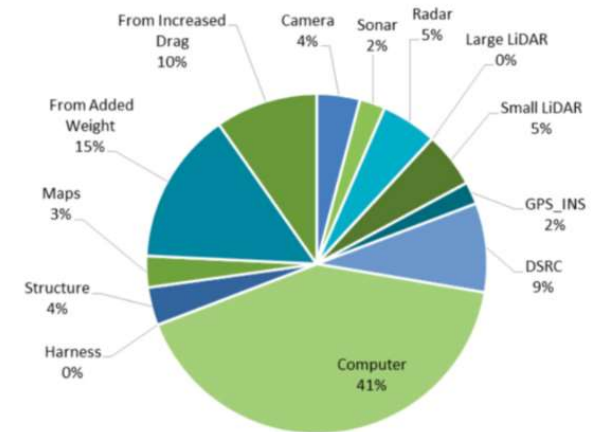
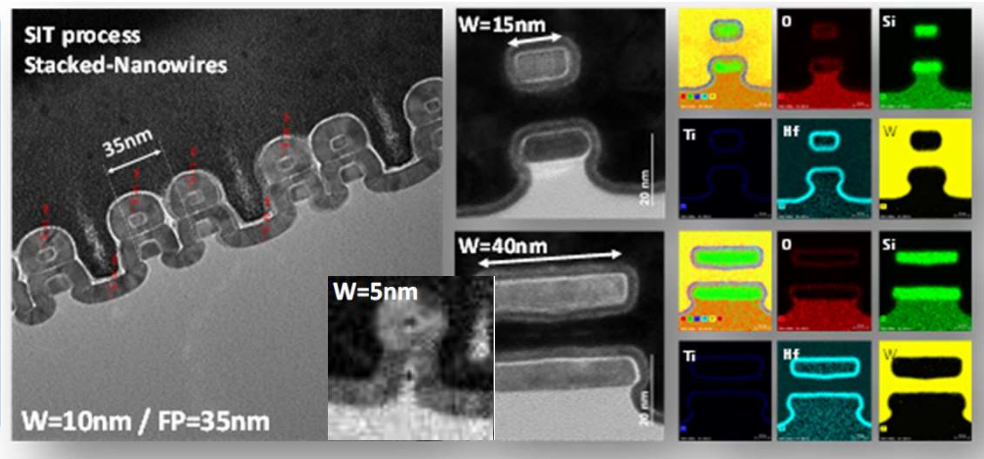


Image: University of Michigan

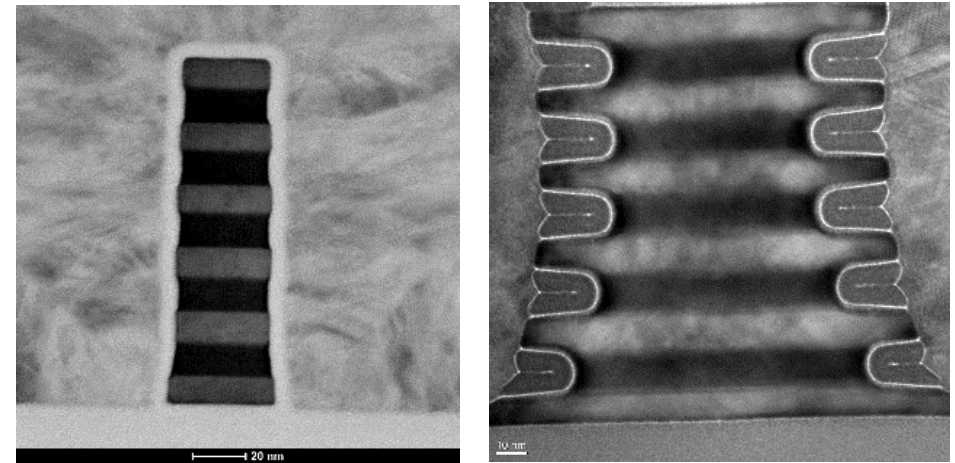
Sources of added energy consumption from Ford Fusion's autonomy system.

## Performance track

- Scaling of nanosheets for sub 5nm node



Standard gate-last for nanosheets

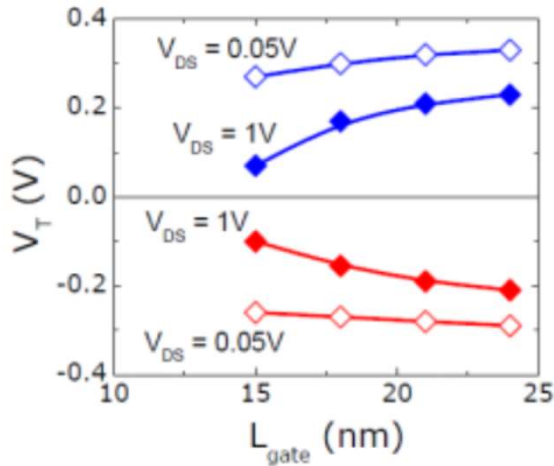


High-aspect ratio (HAR) Gate-last for nanosheets

“Tunability of Parasitic Channel in Gate-All-Around Stacked Nanosheets.” S. Barraud et al. this IEDM

- Power efficiency track

- FDSOI still the best solution and can still be shrunk



O.Faynot, IEDM 2010

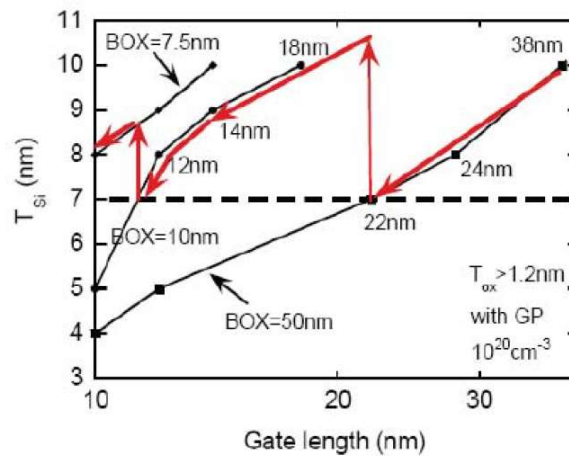


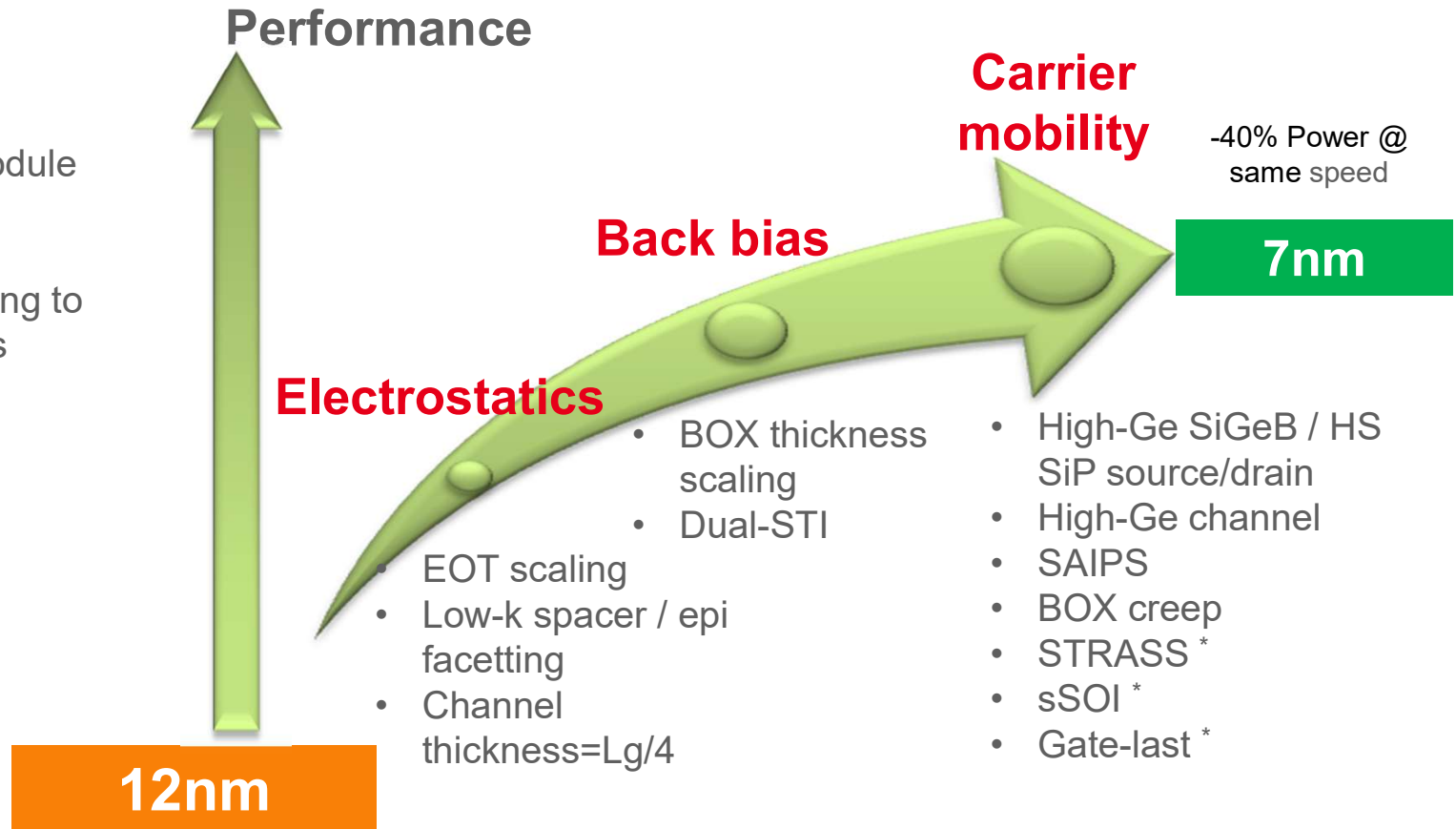
Fig.3: SOI and BOX thicknesses required to achieve a DIBL=100 mV/V as a function of gate length (2)

- Electrostatic control improved by thinning  $T_{BOX}$
- Scalability down to 10nm node
- Devices already processed with 3.5nm SOI film
- Physical limit  $L_g=10nm$  (5nm-3nm node)
- But requires boosters



• **Power efficiency track**

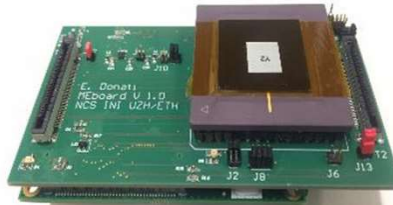
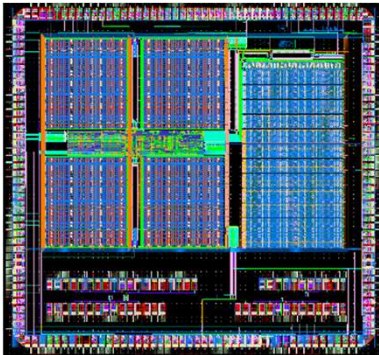
- Individual boosters validated
- No roadblock at module level
- Deployable according to industrial roadmaps



- Power efficiency track
  - Efficiency proven also for new architectures



*Mixed signal spiking neural network chip in ST FDSOI  
28nm technology*



Chip Name	DynapSEL
Process	ST28FDSOI
Supply Voltage	1V
IO Number	176 + (internal 59)
Chip area	2.8mm x 2.6mm
Core Numbers	4 non-plastic cores 1 plastic core
Neuron Type	Analog AExp I&F
Non-plastic Synapse Type	TCAM based 4-bit
Plastic Synapse Type	Linear 4-bit digital
Throughput of Router	1G Events/second
Scalability	16 x16 chips non-plastic core) 4 x4 chips (plastic cores)

	IBM TrueNorth	Intel LoiChi	DynapSEL
Technology	28nm CMOS	14 nm CMOS	28 nm FDSOI
Supply Voltage	0.7-1.05 V	0.5-1.25 V	0.73-1 V
Design Type	Digital	Digital	Mixed-signal
Neurons per core	256	Max 1k	256
Core Area	0.094 mm <sup>2</sup>	0.4 mm <sup>2</sup>	0.36 mm <sup>2</sup>
Computation	Time multiplexing	Time multiplexing	Parallel processing
Fan In/Out	256/256	16/4k	2k/8k
On-line Learning	No	Programmable	STDP
Synaptic Operation / Second / Watt	46 GSOPS/W		300 GSOPS/W
Energy per synaptic operation	26 pJ	23.6 pJ	<2 pJ

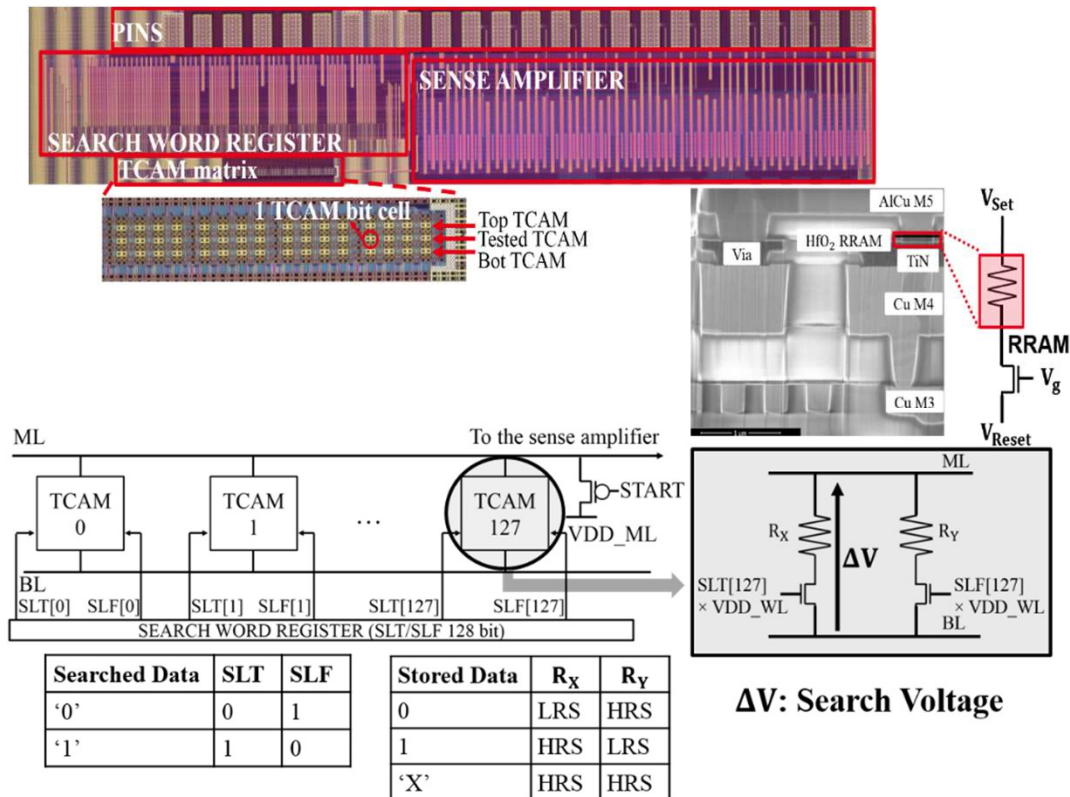


- Introduction of resistive memories as replacement for SRAM, embedded flash and stand-alone

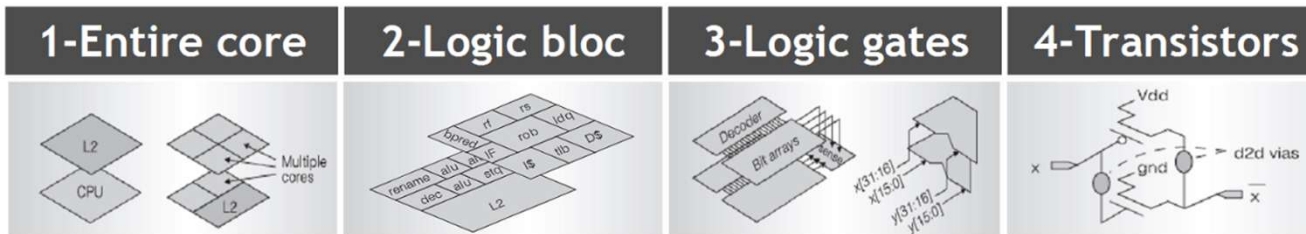
- Increased density
- Lower power
- Better latency
- New architectures like neuromorphic and more generally In-Memory-Computing

- One example: OxRAM-based TCAM

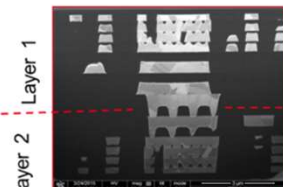
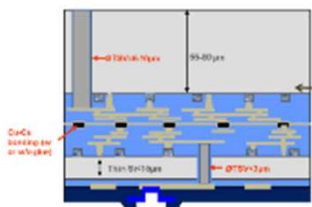
(D. R. B. Ly, et al., "In-depth Characterization of Resistive Memory-Based Ternary Content Addressable Memories", this IEDM)





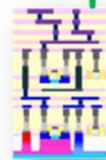


3D Parallel

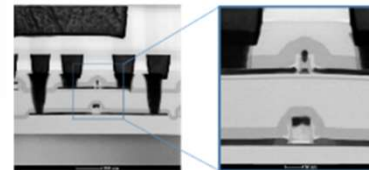


Cu-Cu bonding

3D Sequential



CoolCube™



100µm

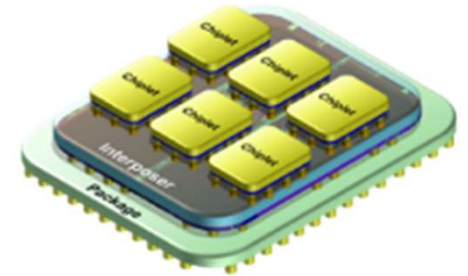
10µm

1µm

100nm

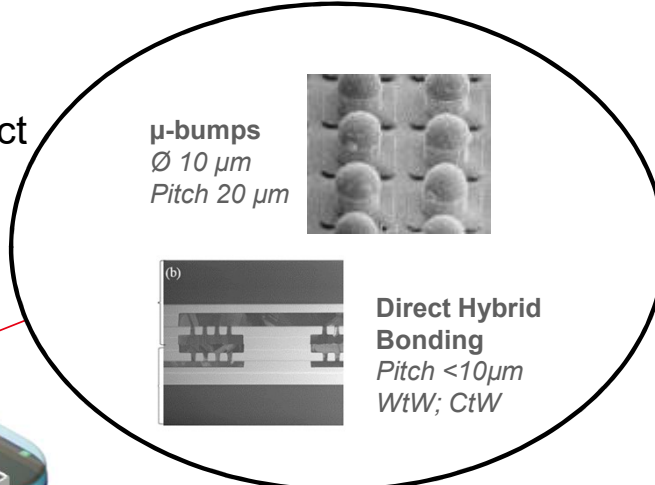
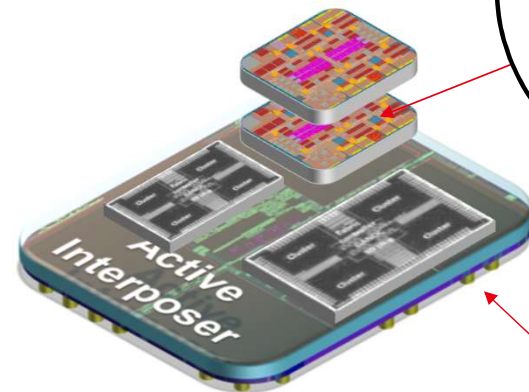
10nm

- Toolbox of 3D technologies to improve communications between functional blocks
- Heterogeneous integration to make possible new architectures both in HPC (digital-memory) and embedded (digital-memory analog sensors)



- Parallel heterogeneous integration, the “chiplet” concept

Inter-dies interconnect



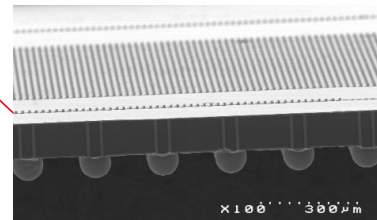
**28nm FDSOI chiplets (x6)**

- Low power compute fabric
- Wide voltage range (0.6V – 1.2V)
- Body biasing for logic boost & leakage ctrl

**65nm Active Interposer**

- Power unit (switched Cap DC-DC conv.)
- Interconnect (Network-on-Chip)
- Test, clocking, thermal sensors, etc

Intra-dies interconnect

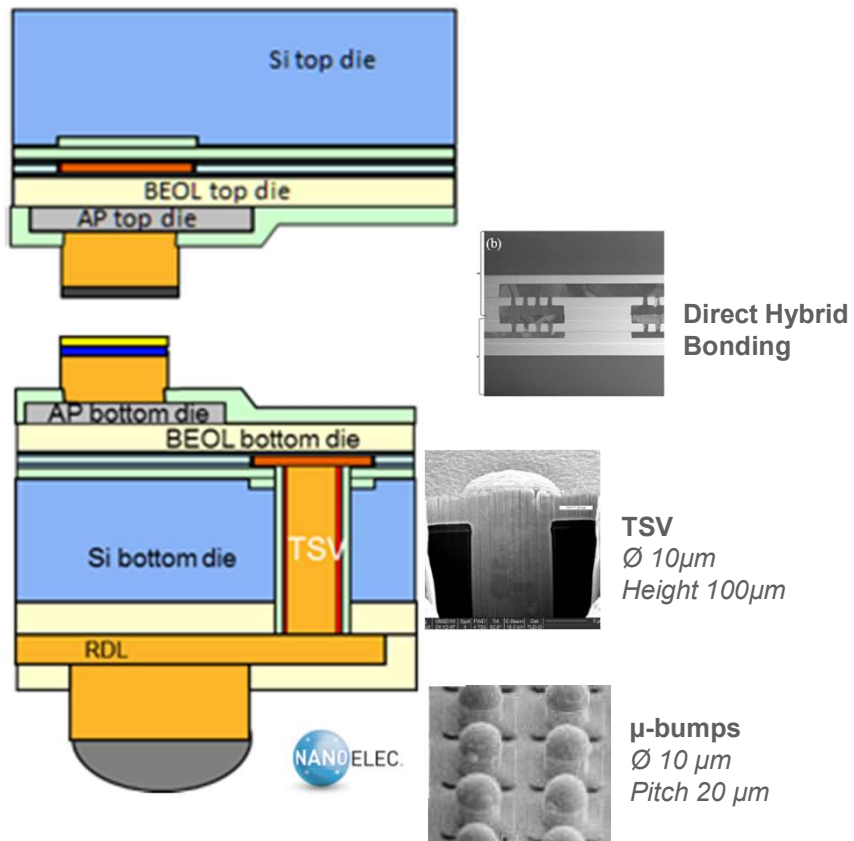


TSV  
Ø 10 μm  
Height 100 μm



This work was funded thanks to the French national program “Programme d’Investissements d’Avenir, IRT Nanoelec” ANR-10-AIRT-05.

• Parallel heterogeneous integration



**28nm FDSOI chipllets (x6)**

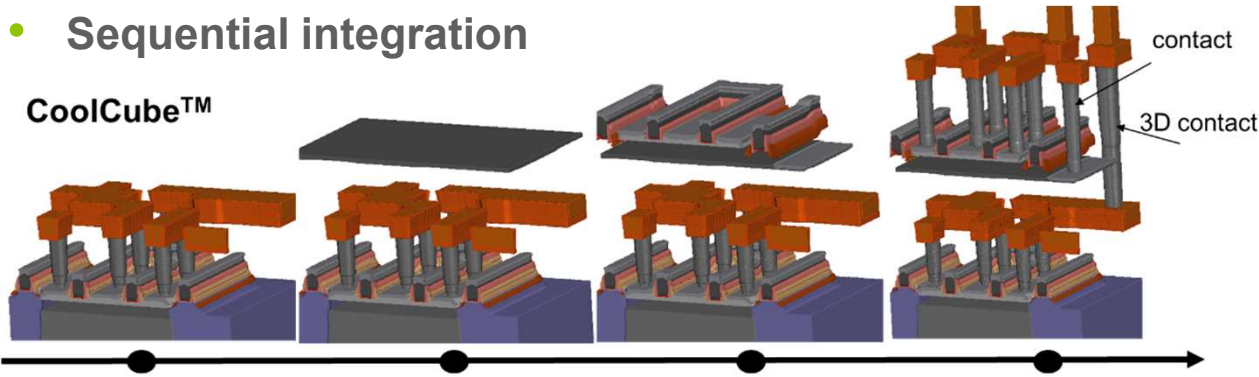
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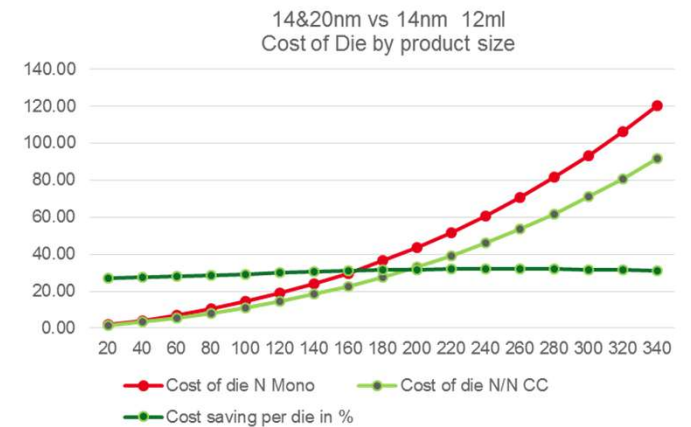
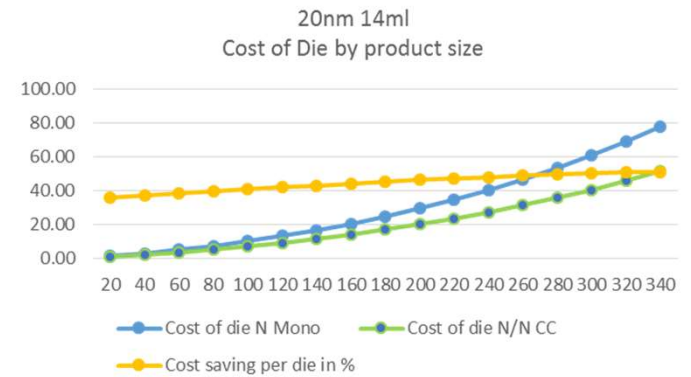
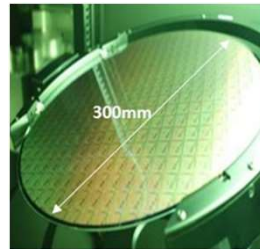
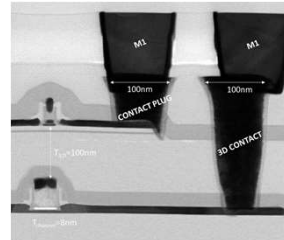
Sequential integration

CoolCube™



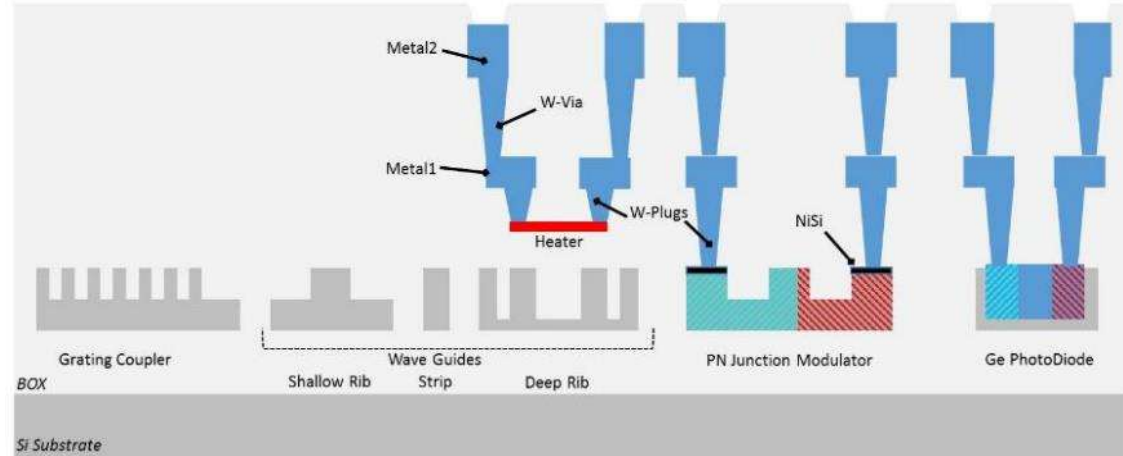
- Extension of FDSOI, but FinFET/FDSOI heterogeneous possible
- 300mm demonstrated
- Reliability demonstrated
- Cost model available

<b>BTI@T=125°C</b> Crit=50mV	<b>VG@10y/3σ, PASS</b> if VG>0.9V
PMOS (TL/BL)	0.98V/1.01V <b>OK</b>
NMOS (TL/BL)	1.26V/1.37V <b>OK</b>

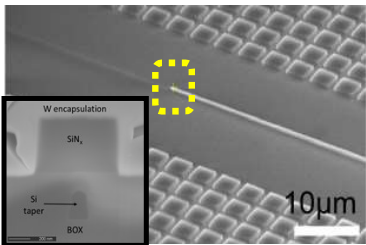


• **Towards 3D Photonics**

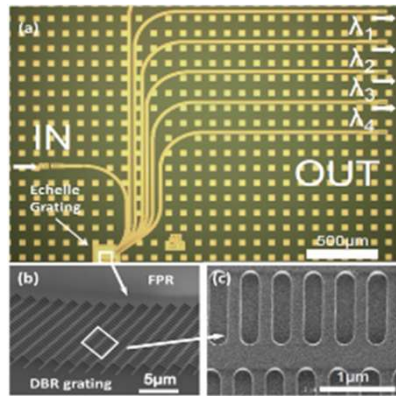
- SOI core photonics process in 300mm
- SiN layer integrated on top of the Si
- SiN-based devices:
  - + low propagation loss
  - + low thermal sensitivity
  - no active device



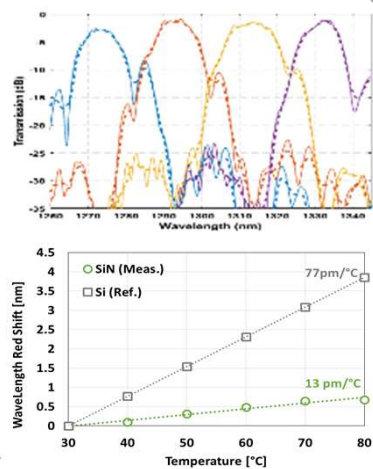
**Low thermal sensitive SiN Mux/DeMux**



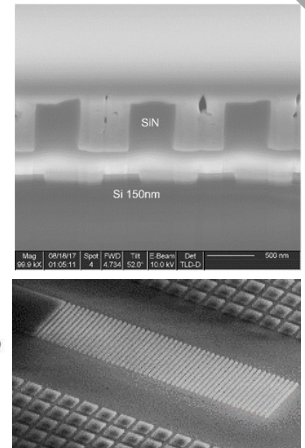
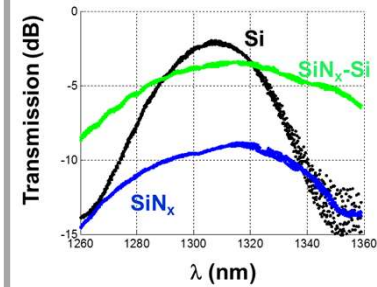
Loss <0.1 dB/transition



C. Sciancalepore et al., SSDM 2017



**High-efficiency & wide bandwidth Si-SiNx grating coupler**

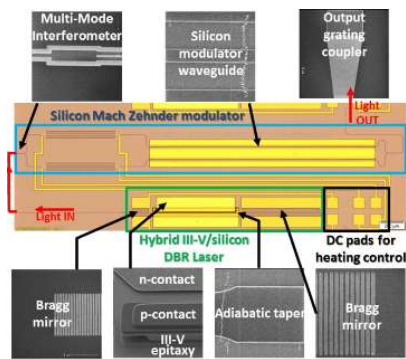


W.D. Sacher, Optical Express, Vol. 22, No. 9, 2014

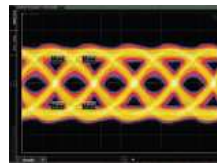
## Heterogeneous III-V on Si integration

- Laser
- Electro-absorption modulator
- Semiconductor optical amplifier
- Localize III-V by die-to-wafer bonding:

### 25Gb/s laser + MZM transmitter



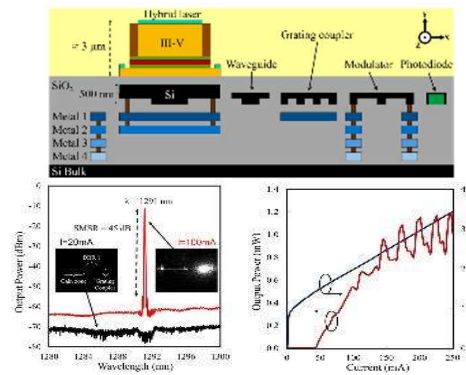
- Co-integration: hybrid III-V/Si DBR laser + Si Mach-Zehnder modulator.



- 25Gb/s transmission @1.3μm up to 10km.

T. Ferrotti et al., 1.3μm hybrid III-V on Silicon Transmitter Operating at 25Gb/s SSDM, (2016)

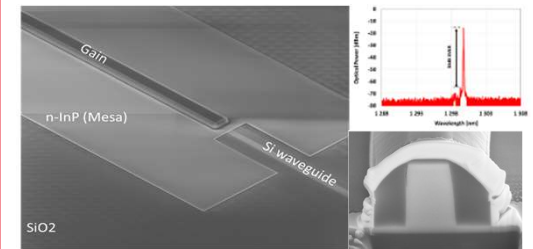
### Back-Side integrated hybrid laser



- New back side integration of a hybrid laser compatible with CMOS based photonic platform.
- Single wavelength behavior with SMSR higher than 35dB.
- Lasing threshold around 45mA with an output power >1.15mW at 200mA.

J. Durel et al., First Demonstration of a Back-Side Integrated Heterogeneous Hybrid III-V/Si DBR Lasers for Si-Photonics Applications, IEDM (2016)

### CMOS-compatible hybrid laser

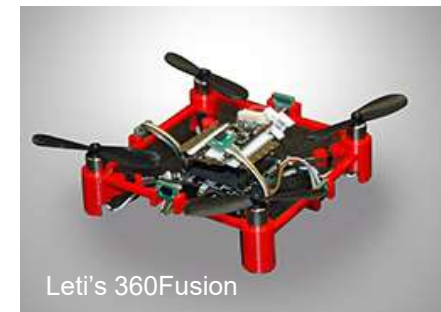
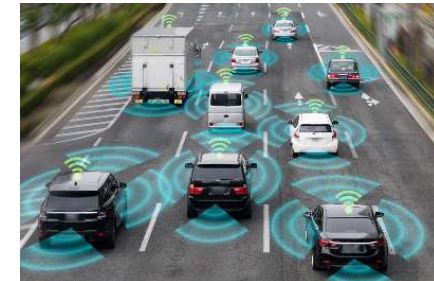
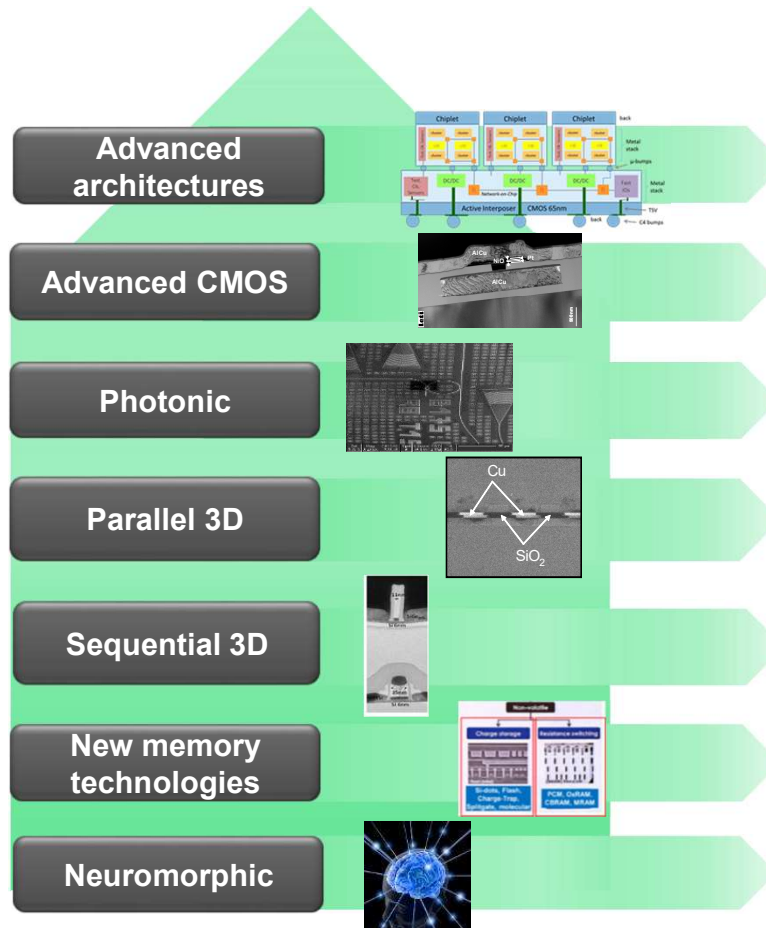


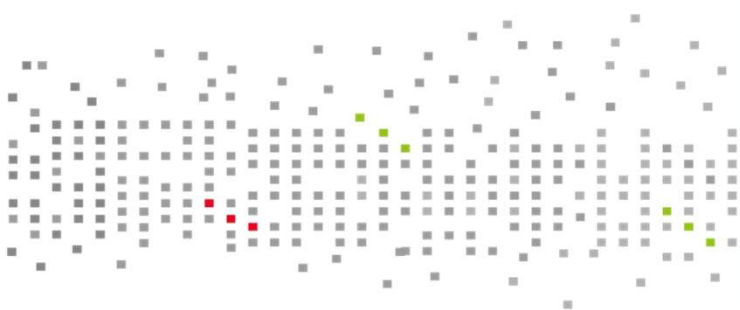
- Front side integration of a hybrid III-V/Si laser in a fully CMOS compatible 200mm technology.
- CMOS compatible metallization (no noble metals) and patterning (no lift-off) processes.
- Single wavelength behavior demonstrated with SMSR higher than 50dB.
- Lasing threshold around 60mA with a 3mW output power at 190mA.

B. Szelag et al., Hybrid III-V/Si DFB laser integration on a 200 mm fully CMOS-compatible silicon photonics platform, IEDM (2017)

## CONCLUSIONS

- Leti keeps providing the development of basic technologies to support the needs of data treatment for the mid and long term
- Specific solutions are studied to provide benefits for specific applications as variation on common core elements
- CEA is a major player to support processes and technologies for European Industry and their partners





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